


<b>Search Notes</b>  	<b>Application/Control No.</b>  10521961	<b>Applicant(s)/Patent Under Reexamination</b>  AKAI ET AL.
	<b>Examiner</b>  Randall Chin	<b>Art Unit</b>  3723

SEARCHED			
Class	Subclass	Date	Examiner
15	104.93	2/11/09	RC
15	209.1	2/11/09	RC
15	210.1	2/11/09	RC
15	231	2/11/09	RC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, OCR, EPO, JPO, DERWENT	2/11/09	RC
Inventor name search	2/11/09	RC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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